

## DM74LS90 Decade and Binary Counters

### General Description

Each of these monolithic counters contains four master-slave flip-flops and additional gating to provide a divide-by-two counter and a three-stage binary counter for which the count cycle length is divide-by-five for the DM74LS90.

All of these counters have a gated zero reset and the DM74LS90 also has gated set-to-nine inputs for use in BCD nine's complement applications.

To use their maximum count length (decade or four bit binary), the B input is connected to the Q<sub>A</sub> output. The input count pulses are applied to input A and the outputs are as described in the appropriate truth table. A symmetrical divide-by-ten count can be obtained from the DM74LS90 counters by connecting the Q<sub>D</sub> output to the A input and applying the input count to the B input which gives a divide-by-ten square wave at output Q<sub>A</sub>.

### Features

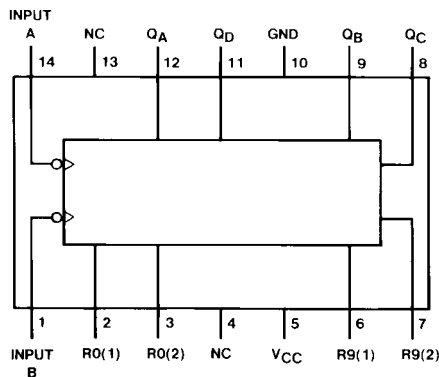
- Typical power dissipation 45 mW
- Count frequency 42 MHz

### Ordering Code:

Order Number	Package Number	Package Description
DM74LS90M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
DM74LS90N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

### Connection Diagram



### Reset/Count Truth Table

Reset Inputs				Output			
R0(1)	R0(2)	R9(1)	R9(2)	Q <sub>D</sub>	Q <sub>C</sub>	Q <sub>B</sub>	Q <sub>A</sub>
H	H	L	X	L	L	L	L
H	H	X	L	L	L	L	L
X	X	H	H	H	L	L	H
X	L	X	L	COUNT			
L	X	L	X	COUNT			
L	X	X	L	COUNT			
X	L	L	X	COUNT			

## Function Tables

BCD Count Sequence (Note 1)

Count	Output			
	Q <sub>D</sub>	Q <sub>C</sub>	Q <sub>B</sub>	Q <sub>A</sub>
0	L	L	L	L
1	L	L	L	H
2	L	L	H	L
3	L	L	H	H
4	L	H	L	L
5	L	H	L	H
6	L	H	H	L
7	L	H	H	H
8	H	L	L	L
9	H	L	L	H

Bi-Quinary (5-2) (Note 2)

Count	Output			
	Q <sub>A</sub>	Q <sub>D</sub>	Q <sub>C</sub>	Q <sub>B</sub>
0	L	L	L	L
1	L	L	L	H
2	L	L	H	L
3	L	L	H	H
4	L	H	L	L
5	H	L	L	L
6	H	L	L	H
7	H	L	H	L
8	H	L	H	H
9	H	H	L	L

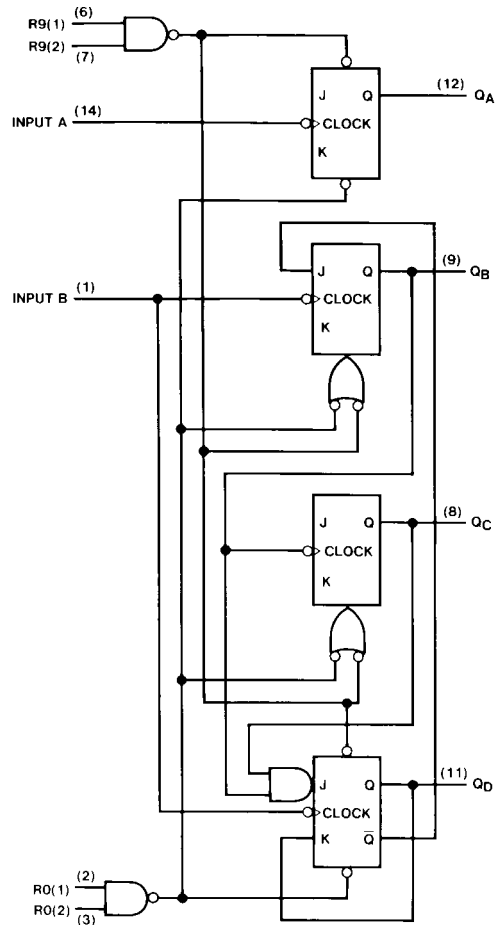
H = HIGH Level  
L = LOW Level  
X = Don't Care

**Note 1:** Output Q<sub>A</sub> is connected to input B for BCD count.

**Note 2:** Output Q<sub>D</sub> is connected to input A for bi-quinary count.

**Note 3:** Output Q<sub>A</sub> is connected to input B.

## Logic Diagram



The J and K inputs shown without connection are for reference only and are functionally at a high level.

**Absolute Maximum Ratings**(Note 4)

Supply Voltage	7V
Input Voltage (Reset)	7V
Input Voltage (A or B)	5.5V
Operating Free Air Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +150°C

**Note 4:** The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the "Electrical Characteristics" table are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

**Recommended Operating Conditions**

Symbol	Parameter	Min	Nom	Max	Units
$V_{CC}$	Supply Voltage	4.75	5	5.25	V
$V_{IH}$	HIGH Level Input Voltage	2			V
$V_{IL}$	LOW Level Input Voltage			0.8	V
$I_{OH}$	HIGH Level Output Current			-0.4	mA
$I_{OL}$	LOW Level Output Current			8	mA
$f_{CLK}$	Clock Frequency (Note 5)	A to $Q_A$	0	32	MHz
		B to $Q_B$	0	16	
$f_{CLK}$	Clock Frequency (Note 6)	A to $Q_A$	0	20	MHz
		B to $Q_B$	0	10	
$t_W$	Pulse Width (Note 5)	A	15		ns
		B	30		
		Reset	15		
$t_W$	Pulse Width (Note 6)	A	25		ns
		B	50		
		Reset	25		
$t_{REL}$	Reset Release Time (Note 5)	25			ns
$t_{REL}$	Reset Release Time (Note 6)	35			ns
$T_A$	Free Air Operating Temperature	0		70	°C

**Note 5:**  $C_L = 15$  pF,  $R_L = 2$  k $\Omega$ ,  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5$ V.

**Note 6:**  $C_L = 50$  pF,  $R_L = 2$  k $\Omega$ ,  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5$ V.

**Electrical Characteristics**

over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 7)	Max	Units
$V_I$	Input Clamp Voltage	$V_{CC} = \text{Min}$ , $I_I = -18$ mA			-1.5	V
$V_{OH}$	HIGH Level Output Voltage	$V_{CC} = \text{Min}$ , $I_{OH} = \text{Max}$ $V_{IL} = \text{Max}$ , $V_{IH} = \text{Min}$	2.7	3.4		V
$V_{OL}$	LOW Level Output Voltage	$V_{CC} = \text{Min}$ , $I_{OL} = \text{Max}$ $V_{IL} = \text{Max}$ , $V_{IH} = \text{Min}$ (Note 8) $I_{OL} = 4$ mA, $V_{CC} = \text{Min}$		0.35 0.25	0.5 0.4	V
$I_I$	Input Current @ Max Input Voltage	$V_{CC} = \text{Max}$ , $V_I = 7$ V $V_{CC} = \text{Max}$ $V_I = 5.5$ V			0.1 0.2 0.4	mA
$I_{IH}$	HIGH Level Input Current	$V_{CC} = \text{Max}$ , $V_I = 2.7$ V			20 40 80	$\mu\text{A}$
$I_{IL}$	LOW Level Input Current	$V_{CC} = \text{Max}$ , $V_I = 0.4$ V			-0.4 -2.4 -3.2	mA
$I_{OS}$	Short Circuit Output Current	$V_{CC} = \text{Max}$ (Note 9)	-20		-100	mA
$I_{CC}$	Supply Current	$V_{CC} = \text{Max}$ (Note 7)		9	15	mA

**Note 7:** All typicals are at  $V_{CC} = 5$ V,  $T_A = 25^\circ\text{C}$ .

**Electrical Characteristics** (Continued)

**Note 8:**  $Q_A$  outputs are tested at  $I_{OL} = \text{Max}$  plus the limit value of  $I_{IL}$  for the B input. This permits driving the B input while maintaining full fan-out capability.

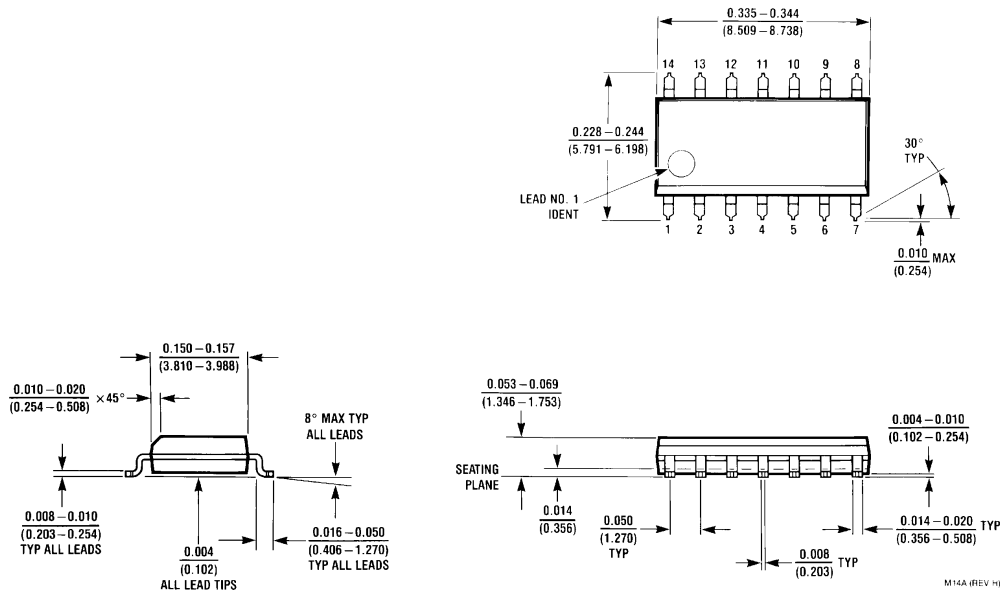
**Note 9:** Not more than one output should be shorted at a time, and the duration should not exceed one second.

**Note 10:**  $I_{CC}$  is measured with all outputs open, both RO inputs grounded following momentary connection to 4.5V and all other inputs grounded.

**Switching Characteristics** at  $V_{CC} = 5V$  and  $T_A = 25^\circ\text{C}$ 

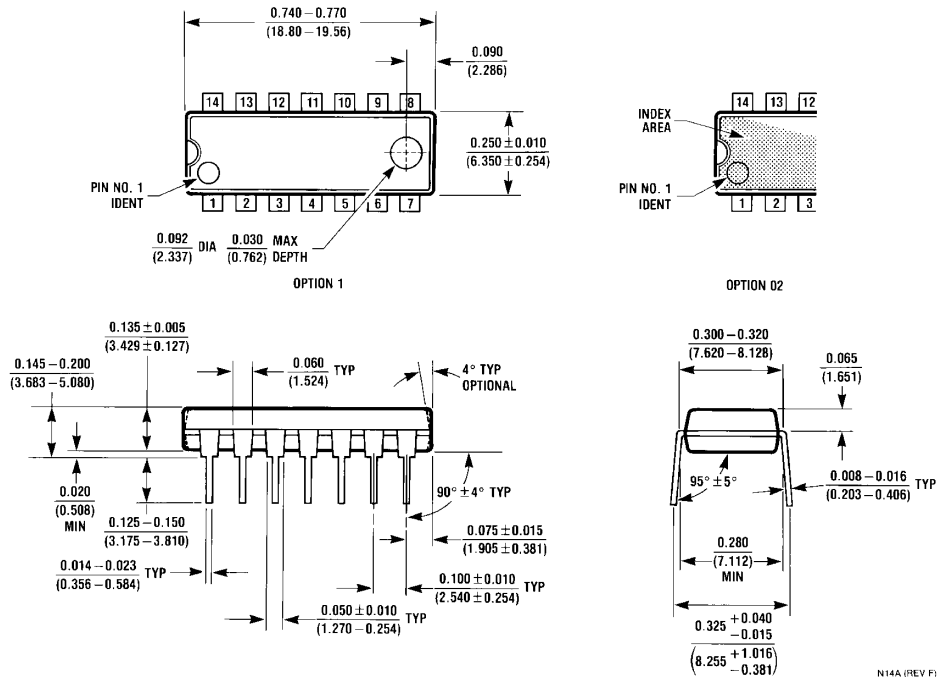
Symbol	Parameter	From (Input) To (Output)	$R_L = 2\text{ k}\Omega$				Units
			$C_L = 15\text{ pF}$		$C_L = 50\text{ pF}$		
			Min	Max	Min	Max	
$f_{MAX}$	Maximum Clock Frequency	A to $Q_A$	32		20		MHz
		B to $Q_B$	16		10		
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	A to $Q_A$		16		20	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	A to $Q_A$		18		24	ns
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	A to $Q_D$		48		52	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	A to $Q_D$		50		60	ns
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	B to $Q_B$		16		23	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	B to $Q_B$		21		30	ns
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	B to $Q_C$		32		37	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	B to $Q_C$		35		44	ns
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	B to $Q_D$		32		36	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	B to $Q_D$		35		44	ns
$t_{PLH}$	Propagation Delay Time LOW-to-HIGH Level Output	SET-9 to $Q_A, Q_D$		30		35	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	SET-9 to $Q_B, Q_C$		40		48	ns
$t_{PHL}$	Propagation Delay Time HIGH-to-LOW Level Output	SET-0 to Any Q		40		52	ns

**Physical Dimensions** inches (millimeters) unless otherwise noted



**14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow  
Package Number M14A**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A**

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